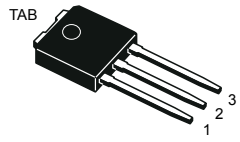
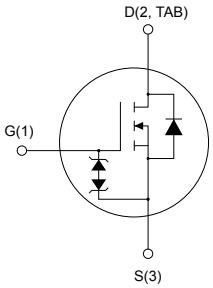
# N-channel 950 V, 4.2 Ω typ., 2 A MDmesh K5 Power MOSFET in an IPAK package




**IPAK**




AM01476v1_tab

## Features

| Order code | $V_{DS}$ | $R_{DS(on)}$ max. | $I_D$ |
|---|---|---|---|
| STU2N95K5 | 950 V | 5 Ω | 2 A |

- Industry's lowest $R_{DS(on)}$ x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

## Applications

- Switching applications

## Description

This very high voltage N-channel Power MOSFET is designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

| Product status link |
|---|
| STU2N95K5 |

| Product summary | |
|---|---|
| **Order code** | STU2N95K5 |
| **Marking** | 2N95K5 |
| **Package** | IPAK |
| **Packing** | Tube |

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

| Symbol | Parameter | Value | Unit |
|---|---|---|---|
| $V_{GS}$ | Gate-source voltage | ±30 | V |
| $I_D$ | Drain current (continuous) at $T_C$ = 25 °C | 2 | A |
| | Drain current (continuous) at $T_C$ = 100 °C | 1.3 | |
| $I_{DM}$(1) | Drain current (pulsed) | 8 | A |
| $P_{TOT}$ | Total power dissipation at $T_C$ = 25 °C | 45 | W |
| dv/dt(2) | Peak diode recovery voltage slope | 4.5 | V/ns |
| dv/dt(3) | MOSFET dv/dt ruggedness | 50 | V/ns |
| $T_{stg}$ | Storage temperature range | -55 to 150 | °C |
| $T_J$ | Operating junction temperature range | | °C |

1. *Pulse width is limited by safe operating area.*
2. *$I_{SD}$ ≤ 2 A, di/dt ≤ 100 A/µs, $V_{DS}$ (peak) ≤ $V_{(BR)DSS}$.*
3. *$V_{DS}$ ≤ 760 V.*

**Table 2. Thermal data**

| Symbol | Parameter | Value | Unit |
|---|---|---|---|
| $R_{thJC}$ | Thermal resistance, junction-to-case | 2.78 | °C/W |
| $R_{thJA}$ | Thermal resistance, junction-to-ambient | 100 | °C/W |

**Table 3. Avalanche characteristics**

| Symbol | Parameter | Value | Unit |
|---|---|---|---|
| $I_{AR}$ | Avalanche current, repetitive or non-repetitive (pulse width limited by $T_J$ max.) | 1 | A |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_J$ = 25 °C, $I_D$ = $I_{AR}$, $V_{DD}$ = 50 V) | 50 | mJ |

# 2 Electrical characteristics

$T_C$ = 25 °C unless otherwise specified.

**Table 4. On/off-state**

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS}$ = 0 V, $I_D$ = 1 mA | 950 | | | V |
| $I_{DSS}$ | Zero gate voltage drain current | $V_{DS}$ = 950 V, $V_{GS}$ = 0 V | | | 1 | µA |
| | | $V_{DS}$ = 950 V, $V_{GS}$ = 0 V, $T_C$ = 125 °C(1) | | | 50 | |
| $I_{GSS}$ | Gate body leakage current | $V_{GS}$ = ±20 V, $V_{DS}$ = 0 V | | | ±10 | µA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS}$ = $V_{GS}$, $I_D$ = 100 µA | 3 | 4 | 5 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS}$ = 10 V, $I_D$ = 1 A | | 4.2 | 5 | Ω |

1. *Specified by design, not tested in production.*

**Table 5. Dynamic**

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| $C_{iss}$ | Input capacitance | $V_{DS}$ = 100 V, f = 1 MHz, $V_{GS}$ = 0 V | - | 105 | - | pF |
| $C_{oss}$ | Output capacitance | | - | 9 | - | pF |
| $C_{rss}$ | Reverse transfer capacitance | | - | 0.5 | - | pF |
| $C_{o(tr)}$(1) | Equivalent capacitance time related | $V_{GS}$ = 0 V, $V_{DS}$ = 0 to 760 V | - | 16 | - | pF |
| $C_{o(er)}$(2) | Equivalent capacitance energy related | | - | 6 | - | pF |
| $R_g$ | Intrinsic gate resistance | f = 1 MHz, $I_D$ = 0 A | - | 16 | - | Ω |
| $Q_g$ | Total gate charge | $V_{DD}$ = 760 V, $I_D$ = 2 A, $V_{GS}$ = 0 to 10 V (see Figure 14. Test circuit for gate charge behavior) | - | 10 | - | nC |
| $Q_{gs}$ | Gate-source charge | | - | 1.5 | - | nC |
| $Q_{gd}$ | Gate-drain charge | | - | 8 | - | nC |

1. *$C_{o(tr)}$ is a constant capacitance value that gives the same charging time as $C_{oss}$ while $V_{DS}$ is rising from 0 to 80% $V_{DSS}$.*
2. *$C_{o(er)}$ is a constant capacitance value that gives the same stored energy as $C_{oss}$ while $V_{DS}$ is rising from 0 to 80% $V_{DSS}$.*

**Table 6. Switching times**

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD}$= 475 V, $I_D$ = 1 A, $R_G$ = 4.7 Ω, $V_{GS}$ = 10 V (see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform) | - | 8.5 | - | ns |
| $t_r$ | Rise time | | - | 13.5 | - | ns |
| $t_{d(off)}$ | Turn-off delay time | | - | 20.5 | - | ns |
| $t_f$ | Fall time | | - | 32.5 | - | ns |

**Table 7. Source-drain diode**

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| $I_{SD}$ | Source-drain current | | - | | 2 | A |
| $I_{SDM}$ (1) | Source-drain current (pulsed) | | - | | 8 | A |
| $V_{SD}$(2) | Forward on voltage | $I_{SD}$ = 2 A, $V_{GS}$ = 0 V | - | | 1.5 | V |
| $t_{rr}$ | Reverse recovery time | $I_{SD}$ = 2 A, di/dt = 100 A/µs, $V_{DD}$ = 60 V (see Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 300 | | ns |
| $Q_{rr}$ | Reverse recovery charge | | - | 1.15 | | µC |
| $I_{RRM}$ | Reverse recovery current | | - | 7.6 | | A |
| $t_{rr}$ | Reverse recovery time | $I_{SD}$ = 2 A, di/dt = 100 A/µs, $V_{DD}$ = 60 V, $T_J$= 150 °C (see Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 525 | | ns |
| $Q_{rr}$ | Reverse recovery charge | | - | 1.90 | | µC |
| $I_{RRM}$ | Reverse recovery current | | - | 7.2 | | A |

1. *Pulse width is limited by safe operating area.*
2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%.*

## 2.1 Electrical characteristics (curves)

**Figure 1. Safe operating area**

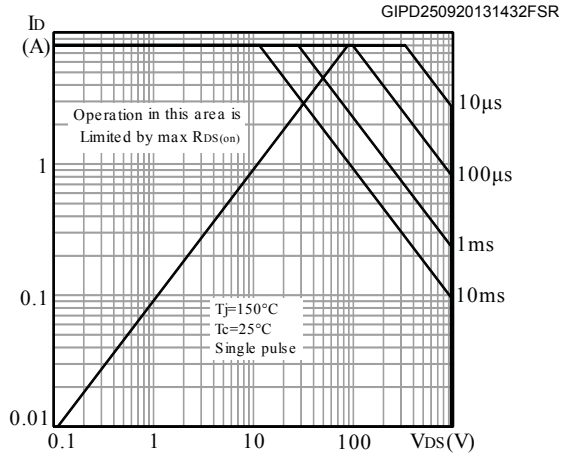



**Figure 2. Normalized transient thermal impedance**

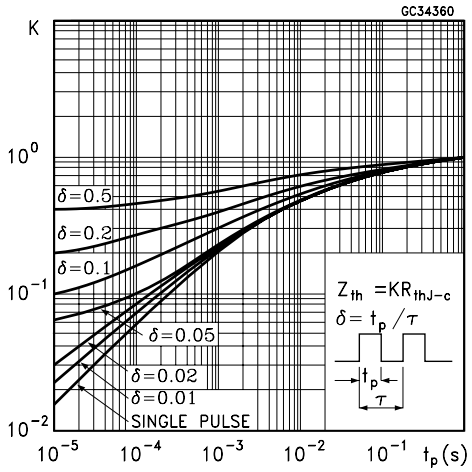



**Figure 3. Typical output characteristics**

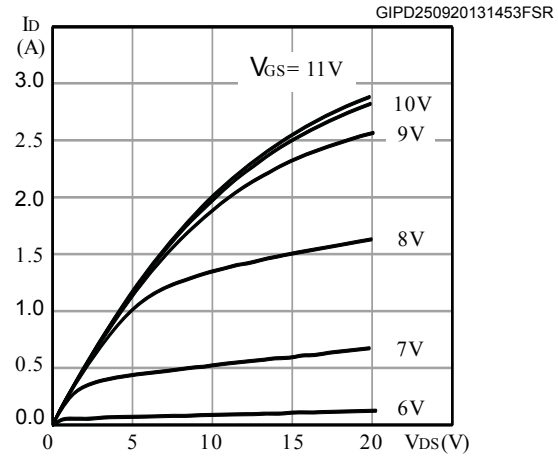



**Figure 4. Typical transfer characteristics**

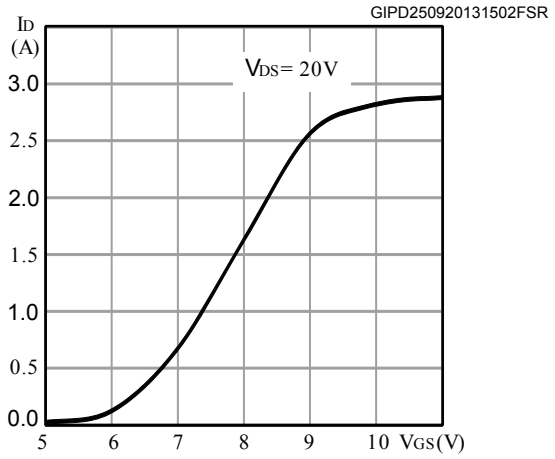



**Figure 5. Typical gate charge characteristics**

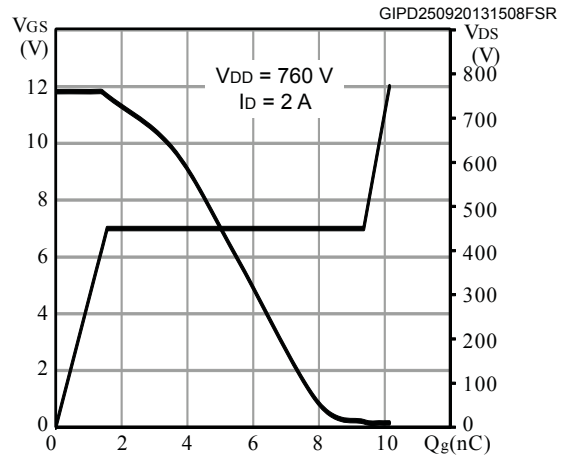



**Figure 6. Typical drain-source on-resistance**

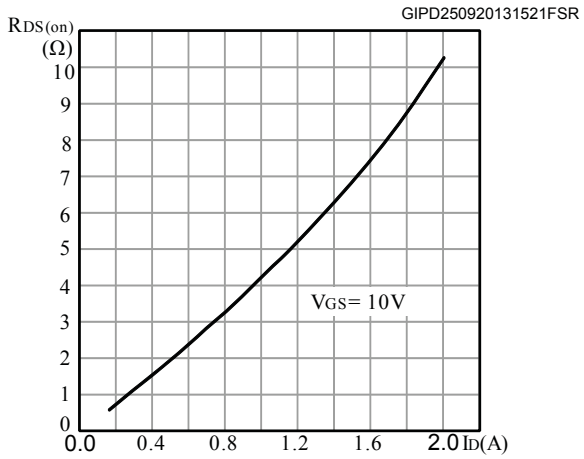


**Figure 7. Typical capacitance characteristics**

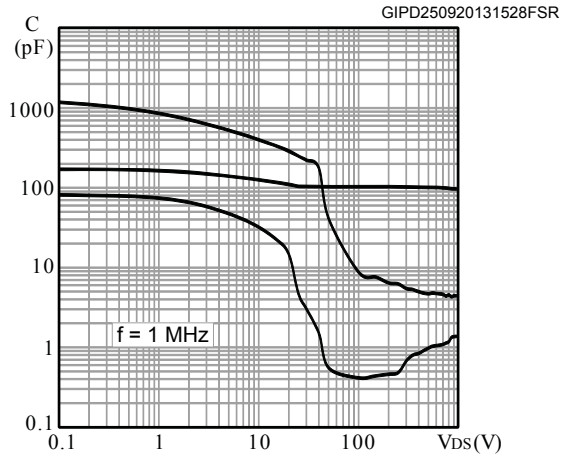



**Figure 8. Output capacitance stored energy**

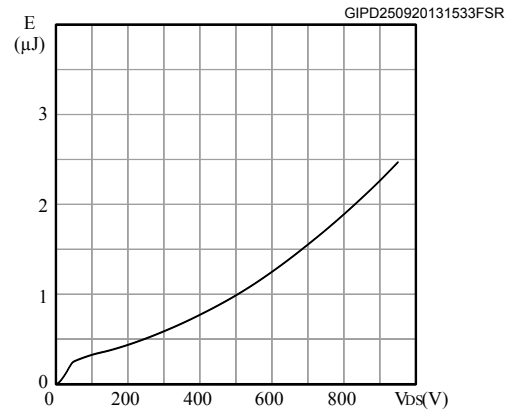



**Figure 9. Normalized gate threshold vs temperature**

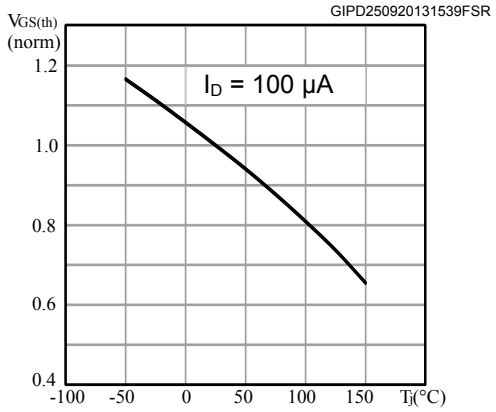



**Figure 10. Normalized on-resistance vs temperature**

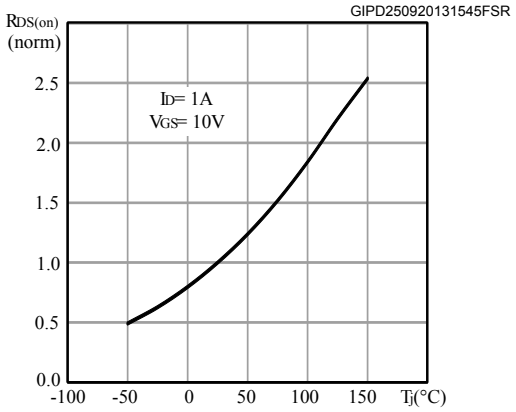



**Figure 11. Normalized breakdown voltage vs temperature**

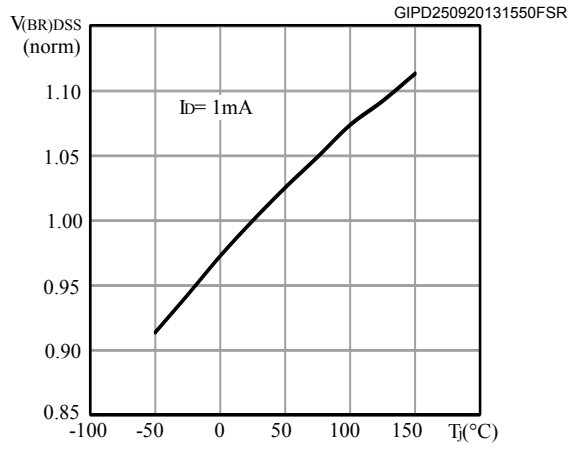
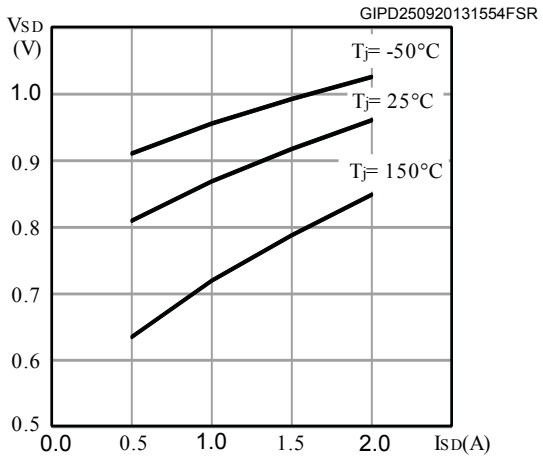
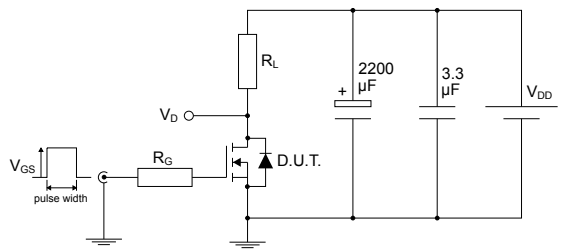



**Figure 12. Typical reverse diode forward characteristics**



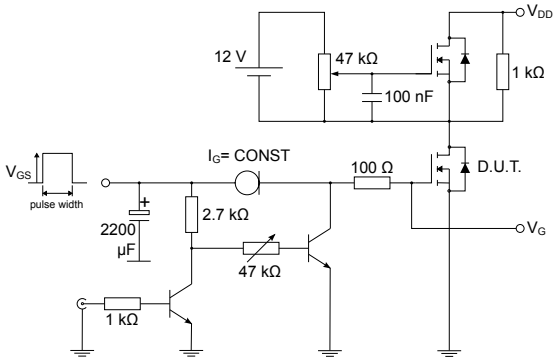
# 3 Test circuits

**Figure 13. Test circuit for resistive load switching times**



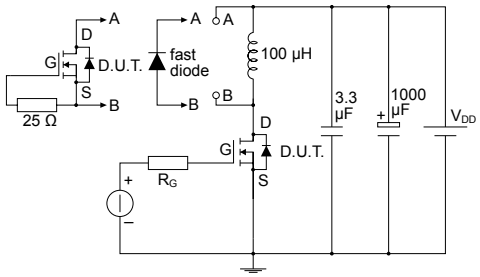

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**Figure 14. Test circuit for gate charge behavior**



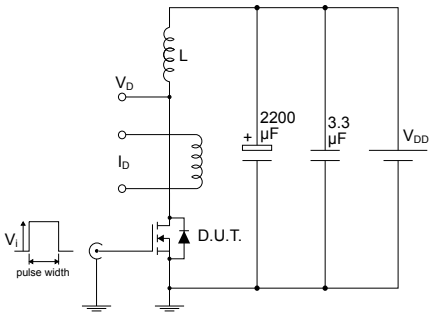

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**Figure 15. Test circuit for inductive load switching and diode recovery times**



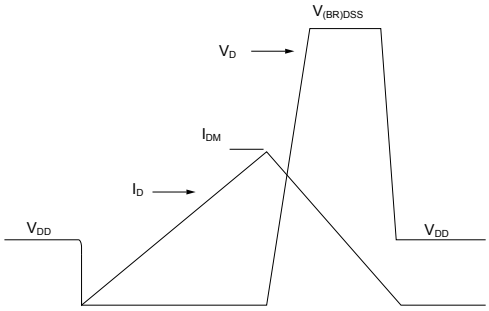

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**Figure 16. Unclamped inductive load test circuit**



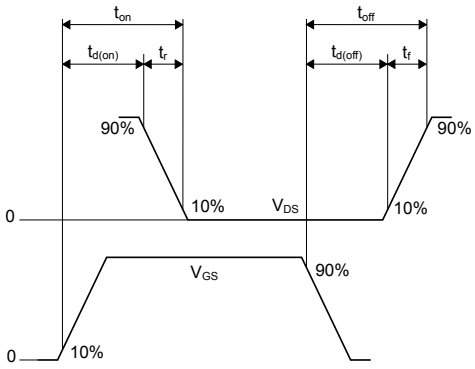

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**Figure 17. Unclamped inductive waveform**




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**Figure 18. Switching time waveform**



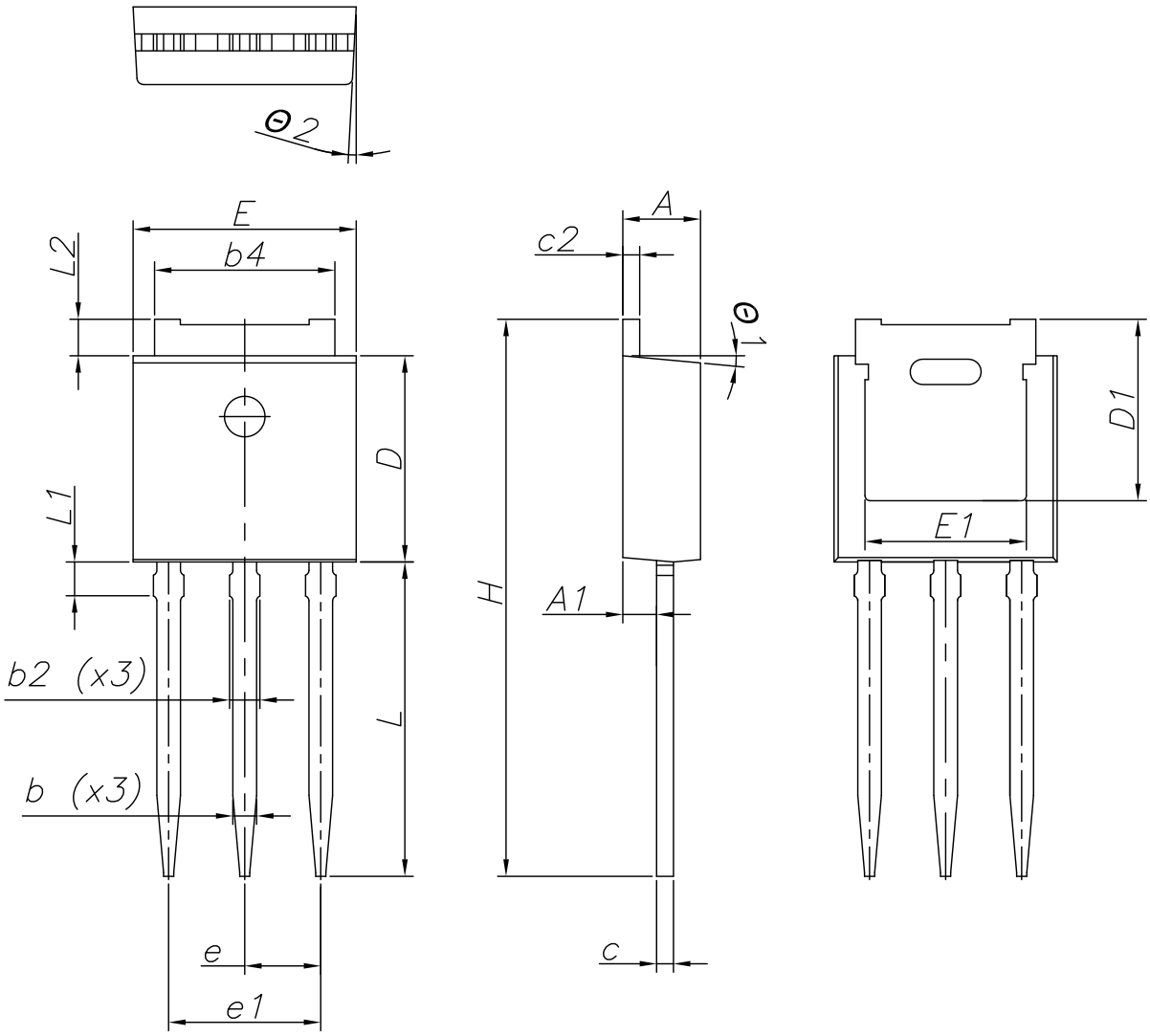

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# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

## 4.1 IPAK (TO-251) type C package information

**Figure 19. IPAK (TO-251) type C package outline**




0068771_IK_typeC_rev16

Table 8. **IPAK (TO-251) type C package mechanical data**

| Dim. | mm | | |
|---|---|---|---|
| | Min. | Typ. | Max. |
| A | 2.20 | 2.30 | 2.35 |
| A1 | 0.90 | 1.00 | 1.10 |
| b | 0.66 | | 0.79 |
| b2 | | | 0.90 |
| b4 | 5.23 | 5.33 | 5.43 |
| c | 0.46 | | 0.59 |
| c2 | 0.46 | | 0.59 |
| D | 6.00 | 6.10 | 6.20 |
| D1 | 5.20 | 5.37 | 5.55 |
| E | 6.50 | 6.60 | 6.70 |
| E1 | 4.60 | 4.78 | 4.95 |
| e | 2.20 | 2.25 | 2.30 |
| e1 | 4.40 | 4.50 | 4.60 |
| H | 16.18 | 16.48 | 16.78 |
| L | 9.00 | 9.30 | 9.60 |
| L1 | 0.80 | 1.00 | 1.20 |
| L2 | 0.90 | 1.08 | 1.25 |
| θ1 | 3° | 5° | 7° |
| θ2 | 1° | 3° | 5° |

## Revision history

Table 9. **Document revision history**

| Date | Revision | Changes |
|---|---|---|
| 25-Sep-2013 | 1 | First release. |
| 23-Nov-2023 | 2 | The part numbers STD2N95K5, STF2N95K5 and STP2N95K5 have been moved to separate datasheets and the document has been updated accordingly.<br>Removed Gate-source Zener diode table<br>Updated Section 4 Package information.<br>Minor text changes. |

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